STEREO IMPACT SEP Crash during TB

PROBLEM REPORT PR-2011 5/19/2005

 $PR\ Numbers:\ 1xxx=UCB,\ 2xxx=Caltech/JPL,\ 3xxx=UMd,\ 4xxx=GSFC/SEP,\ 5xxx=GSFC/Mag,$

6xxx=CESR, 7xxx=Keil, 8xxx=ESTEC, 9xxx=MPAe				
Assembly: SEP			SubAssembly: SEP Central	
Component/Part Number:			Serial Number: FM1	
Originator: Branislav Kecman			Organization: Caltech	
Phone: (626) 395-4264			Email: kecman@srl.caltech.edu	
Failure Occurred During (Check one √)				
☐ Functional test	√ Qualification test		S/C Integration	☐ Launch operations
Environment when failure occurred:				
☐ Ambient	☐ Vibration		Shock	☐ Acoustic
☐ Thermal	☐ Vacuum		Thermal-Vacuum	□ EMI/EMC
Problem Description				
before LET reboot command was issued. Power-cycle solved the problem. During T/V test on 6/21/2005, at -15 °C SEP Central crashed again while a series of repetitive LET reboot commands was being sent to LET. SEP reset command solved the problem.				
Analyses Performed to Determine Cause Command log reviewed for command syntax and command sequence, but no issues were found.				
As part of PFR 2014 investigation it was determined that a bit-flip problem in SEP Central memory could cause a symptom like this.				
Corrective Action/ Resolution				
 √Rework □ Repair □ Use As Is □ Scrap 5/28/2005 Retested FM1 SEP Main Assembly at -10 °C in thermal chamber at Caltech, but could not reproduce the anomaly. The instrument wasn't able to get colder than -10 °C due to the insulation provided by bagging and purging. 7/31/2005 Memory chip replaced on SEP Central Logic Board and it apparently solved this problem for good (Reference PFR 2014). The FM1 unit passed re-qualification T/V test between 8/8/2005 – 8/11/2005. Date Action Taken: 5/28/2005 – 7/31/2005 Retest Results: Passed 				
Corrective Action Required/Performed on other Units □ Serial Number(s): N/A				
Closure Approvals				
	Subsystem Lead: CT Project Manager: IMPACT QA: Instrument Manager:	_Bran	islav Kecman	Date:_8/31/05 Date Date: Date: